

Playing an important role in maintaining quality and improving productivity.

Probes

Assembly

Our probes are designed based upon inspection targets to ensure contact with contact points, with various ingenuity being employed in regards to shapes and materials. For example, in the case of high-speed testing of ceramic chip capacitors in which high levels of friction resistance are required, we offer ultra-hard probes made from ultra-hard alloys. By optimizing contact points, increased probe durability and improvements in productivity can be achieved.

Product features

- Optimized specifications can be proposed to match inspection targets
- Customization of standard parts based on customer requests is possible
- Increased durability, as well as improved non-adjusted ratios and productivity improvements achieved through optimization

Product applications

Connecting parts for conduction inspections and electrical performance inspections of semiconductors, electrical devices, batteries, and automotive wiring, etc.

